

DI CMOS **Protected Dual SPST Analog Switch**

ADG200

FEATURES

Latch-Proof DI CMOS

Overvoltage-Proof: VSUPPLY ±25V Superior DG-200 Replacement Break-Before-Make Switching Action

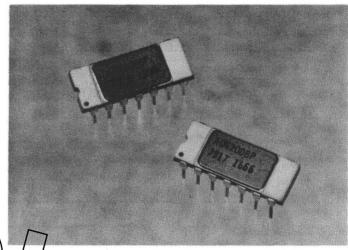
 R_{ON} : 100 Ω max over Full Temperature Range

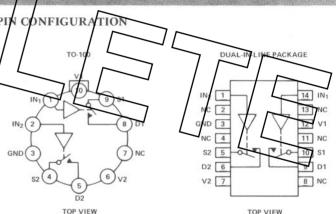
Direct TTL/CMOS Interface

GENERAL DESCRIPTION The ADG200 is a dual single-pole-single-throw analog switch

In the ON condition, the switch conducts current in either direction, maintaining nearly constant ON resistance over the entire analog signal range. In the OFF condition, the switch blocks voltages of peak values equal to the switch V+ and Vsupplies. Switch action is break-before-make. The digital inputs interface directly to TTL or CMOS logic over the full operating temperature range.

Fabricated using an advanced monolithic dielectrically-isolated CMOS process, the ADG200 is a superior plug-in replacement for the DG200. The ADG200 provides additional advantages (over the DG200) of: overvoltage protection to ±25V beyond the power supplies, total latch-free operation, much lower power dissipation (30mW max) and faster switching time.





SWITCH STATES ARE FOR LOGIC "1" INPUT (POSITIVE LOGIC)

ORDERING INFORMATION

Commercial 0 to +70°C		ustrial to +85°C	Military -55°C to +125°C			
Plastic	Ceramic	TO-100	Ceramic	TO-100		
ADG200CJ	ADG200BP	ADG200BA	ADG200AP	ADG200AA ADG200AA/883		

Note: "/883" version is 100% screened to MIL-STD-883, class B as per note 7, page 2.

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West Coast

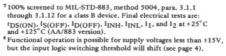
Mid-West 714/842-1717 312/894-3300

Texas 214/231-5094

SPECIFICATIONS

		MAX LIMITS								TEST CONDITIONS ⁸	
and a comparated		TYP ¹ +25°C	AA, AP Suffix -55°C ² +25°C +125°C		BA, BP/CJ Suffix -25/0°C ² +25°C +85/70°C ²		UNITS	Unless Noted $V_1 = +15V$ $V_2 = -15V$, GND = 0V			
CHARACTERISTIC	C.	+25 C	-33 C	+25 C	+125 C	-23/0 C	+25 C	+83//U C	UNITS	V ₂ = -15V, GND = 0V	
SWITCH											
rDS(ON)	Drain-Source	60	70	70	100	80	80	100	Ω	$V_D = 10V$	$V_{IN} = 0.8V$
	ON Resistance	40	70	70	100	80	80	100		V _D = -10V	l _S = 0.1mA
I _{S(OFF)}	Source OFF	0.2	500	2	500	500	5	500		$V_S = 10V, V_D = -10V$	
	Leakage Current	-0.2	-500	-2	-500	-500	-5	-500	nA	$V_S = -10V, V_D = 10V$	$V_{IN} = 2.4V$
-D(OIII)	Drain OFF	0.3 -0.3	500	2 -2	500	500	5	500		$V_D = 10V, V_S = -10V$ $V_D = -10V, V_S = 10V$	
	Leakage Current Channel ON	0.1	-500 500	2	-500 500	-500 500	-5 2	-500 500		$V_D = -10V, V_S = 10V$ $V_D = V_S = 10V$	
I _{D(ON)} ³	Leakage Current	-0.1	-500	-2	-500	-500	-2	-500		$V_D = V_S = -10V$	$V_{IN} = 0.8V$
INPUT	Dealing Current	+	-							D 3	
I _{INH}	Input Current		-10	-1	-10	-10	-1	-10	μА	$V_{IN} = 2.4V$	
INH	Input Voltage High		10	1	10	10	1	10	μΛ	V _{IN} = 15V	
I _{IN(PEAK)} 4	Peak Input Current		-								
- Maria Erens)	Required for			NO	T APPLICA	BLE4					
	Transition										
I _{INL} Input Current			-10	-1	-1 -10	-10	-1	-10	μΑ	$V_{IN} = 0V$	
	Input Voltage Low										
DYNAMIC	1 ~										
ton	Turn-ON Time	300	10			1000 ²			ns	$V_{IN} = 3.5V \text{ to } 0V$	$R_L = 1k\Omega$, $C_L = 35pF$
tOFF	Turn OFF Time ⁵	120		500 ²			500 ²			$V_{IN} = 0V \text{ to } 3.5V$	$V_S = \pm 5V$
C _{S(OFF)}	Source OFF Capacitance	1)							pF	$V_S = 0V$, $V_{IN} = 5V$	
C _D (OKF)	Dryin OFF Capacitance	11							pF	$V_{\rm D} = 0 \rm V, V_{\rm IN} = 5 \rm V$	f = 140kHz
$C_{D(ON)} + C_{S(ON)}$	Channel ON Capacitance	28		\ /		1		7	pF	$V_D = V_S = 0V$ $V_{IN} = 0V$	
OFF Isolation ⁶		64		$\neg \vdash \uparrow$	T				dig	$V_{IN} = 5V$, $R_L = 1k\Omega$,	Cr = 15pF
OI I ISOMEON		1							1 ~	$V_S = 7V_{rms}$, $f = 500kHz$	
SUPPLY				$\overline{}$			7 /				
I ₁	Positive Supply Current	0.02	2	1	2	1	1 1	2	mA		
I ₂	Negative Supply Current	-0.02	-2	-1	\ <u></u>	-2	I_{i}	-2	mA	Both Channels ON: VI	160
		-						$\overline{}$		\sim	$\overline{}$
I ₁	Positive Supply Current	0.1	2	1	2	2	1	_7/	m.A	Both Channels OFF; V	IN = 5V
12	Negative Supply Current	-0.02	-2	-1	-2	-2	-1	-2 4	mA		
PRICES	1-24 25-	99 100	-499 500	0-999 1	K				\$	├ / [/	
ADG200CJ	3.50 3.0				2.00						/
ADG200BP	11.00 8.5				6.50						
	13.00 10.0				7.75 2.00						_
ADG200AP											
ADG200AP ADG200BA ADG200AA	3.50 3.0 11.00 9.0				7.00						

ESD (Electro-Static-Discharge) sensitive device. The digital control inputs are zener protected; however, permanent damage may occur on unconnected devices subject to high energy electrostatic fields. Unused devices must be stored in conductive foam or shunts. The protective foam should be discharged to the destination socket before devices are removed.



Specifications subject to change without notice.



ABSOLUTE MAXIMUM RATINGS

V _{IN} (Digital Input) to Ground
V _S or V _D to V ₁
(1 second surge) +25V, -40V
(continuous) +20V, -35V
V _S or V _D to V ₂
(1 second surge)25V, +40V
(continuous)
V ₁ to Ground0.3V, +17V
V ₂ to Ground+0.3V, -17V
Current, Any Terminal Except S or D 30mA
Current, S or D
Current, S or D Pulsed
(1ms, 10% duty cycle max)

Operating Temperature
AA, AP Suffix
BA, BP Suffix25°C to +85°C
CJ Suffix
Storage Temperature
CJ Suffix65°C to +125°C
All Others
Power Dissipation (Package)*
Metal Can**
14 Pin Ceramic DIP*** 825mV
14 Pin Plastic DIP****

- Devices with all leads welded or soldered to printed circuit board
- Derate 6mW/°C above +75°C
- Derate 11mW/°C above +75°C **** Derate 6.5mW/°C above +25°C

¹Typical values for information only, not guaranteed or production tested.

²Guaranteed, not subject to 100% production test.

^{&#}x27;Guaranteed, not subject to 100% production test.

'lip(ON) is leakage from driver gate into ON switch.

Digital inputs are MOS gates. Typical leakage (+25°C) is less than 1 nanoamp.
This is in contrast to other designs which require typically 150µA to switch.

Switch action is guaranteed break-before-make.

OFF isolation (dB) = 20 log V_S/V_D where V_S = input to OFF switch and V_D = output.

CAUTION:

CIRCUIT DESCRIPTION

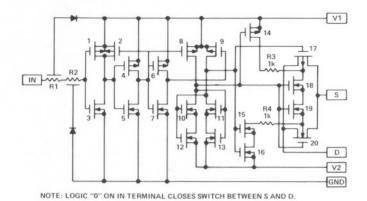


Figure 1. Schematic Diagram (1 of 2 channels)

CMOS devices make excellent inalog switches, however, problems with overvoltage and letch-up phenomenon necessitate protection circuitry. However, these protection circuits either cause degradation of important switch parameters such as RON or leakage, or provide only limited protection in the event of overvoltage.

The ADG200 switch utilizes a dielectrically-isolated CMOS fabrication process to eliminate the four-layer structure found in junction-isolated CMOS, thus providing latch-free operation.

A typical switch channel is shown in Figure 1. The output switching element consists of device numbers 17 and 20. Operation is as follows: for an "ON" switch, the gate of device 20 is \dot{V}_1 and the gate of device 17 is V_2 from the driver circuits. Device numbers 14, 15, and 16 are "OFF" and numbers 18 and 19 are "ON". Hence, the back-gates of the P- and N-channel output devices (numbers 17 and 20) are tied together and floating. Floating the output switch back-gates with the signal input provides a flatter R_{ON} versus V_S response.

For an "OFF" switch, device numbers 18 and 19 are "OFF", and the back-gates of devices 17 and 20 are tied through $1k\Omega$ resistors R_3 and R_4 to the respective supply voltages through the "ON" devices 14, 15, and 16.

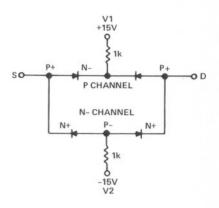


Figure 2. ADG200 Output Switch Diode Equivalent Circuit

If a voltage is applied to the S or D terminals which exceeds V_1 or V_2 , the S- or D-to-back-gate diode is forward biased; however, R_3 and R_4 provide current limiting action (Fig. 2).

Consequently, without external current limiting resistance (or increased R_{ON}), the ADG200 series switches provide:

1 Latch-proof operation.
2. Overvoltage protection 25V beyond the V or V2

supply voltage.

An equivalent execut of the output switch element in Figure 2 shows that, indeed, the $1 k\Omega$ limiting resistors are in series with the back-gates of the P- and N-channel output devices – not in series with the signal path between the S & D terminals.

In some applications it is possible to run on a parasitic NPN (drain to back-gate to source of the N-channel) transistor which causes device destruction under certain conditions. This case will only manifest itself when a negative overvoltage (and not a positive overvoltage) exists with another voltage source on the other side of the switch. Current limitation through external resistors (200Ω) or the output of op amps will prevent damage to the device.

V₁ = +15V

V2 = -15V

500

400 ≌

300

200

100

25

45

SWITCHING TIME

Dimensions shown in inches and (mm).

14-PIN CERAMIC DIP

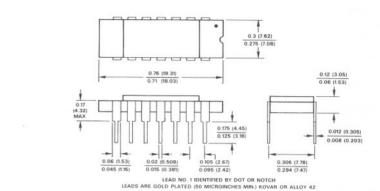


Figure 3. Switching Time vs. Temperature

TEMPERATURE - °C

65

VIN = 0V TO 5V

ton

toff

85

105

125

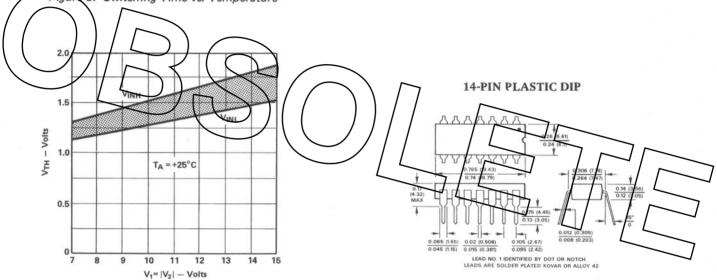
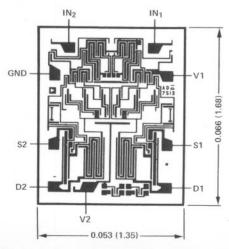


Figure 4. Input Logic Threshold vs. Power Supply Voltage

BONDING DIAGRAM

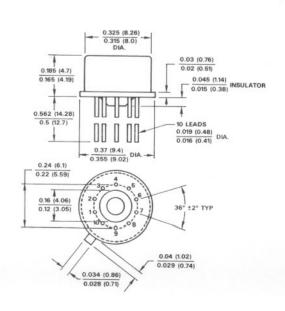
Dimensions shown in inches and (mm).



NOTES:

1. BOND GND PIN FIRST TO MINIMIZE ESD HAZARD. 2. BONDING PADS ARE 0.004 \times 0.004 INCHES (0.102 \times 0.102mm).

TO-100



C486a-5-10/79